SiD and ILD Analyses of the WW Benchmark

Tim Barklow and Aura Rosca

Jan 25, 2013

Selection of e⁺e⁻->W⁺W⁻->qqlv

- SiD Analysis
 - One isolated lepton, jet based isolation
 - Two jets, kt algorithm with R=0.7
 - $N_{PFO}(\text{in jets}) > 12$
 - -60<M_W^{had}<100 GeV
 - M^{*lep*}_W < 250 GeV
 - $-E_{W}^{had} > 300 \text{ GeV}$

- ILD Analysis
 - N_{PFOS} > 15, E_{vis} < 1200 GeV, $M_{vis} > 100 \text{ GeV}, P_T > 5 \text{ GeV}$
 - One isolated lepton, cone based isolation
 - Two jets, kt algorithm with R=1.3
 - 2C kinematic fit
 - $\Box \tau_{discr} > 1$
 - $40 < M_{W}^{fit} < 120 \text{ GeV}$
 - $-\cos\theta_{W} > -0.95$
- N_{sianal} = 150415 (lumi 500 fb⁻¹,

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 $Pe^{-}, Pe^{+}=-0.8, 0.2)$
 - $Pe^{-}, Pe^{+}=-0.8, 0.2), eff = 36\%$

Background Processes

- SiD analysis:
 - Complete SM processes: 2f, 4f, 6f, $\gamma\gamma/e\gamma/minijets$
- ILD analysis:
 - 2f, 4f, 6f
 - Missing: γγ/eγ/minijets
 - First look at some eγ->3f processes without Weiz-Will γ, but very low statistics.
 - Appears manageable with tighter cuts on the fit probability $+E_{W}^{had}$
 - Expect a reduction of the efficiency by a factor ~1.8 (needs additional studies) and consequently an increase of the statistical error by ~√1.8.

Polarization Measurement

Blondel method

Angular fit of the W production angle



Summary

 $\sqrt{s} = 1$ TeV, lumi 500 fb⁻¹ for each configuration -0.8,0.2/0.8,-0.2

ILD		ILD (estimate)		SiD	
Signal: qql∨ Bkgd.: 2f, 4f, 6f		Account for γγ/eγ bkgd.		Signal: qqlv + qqqq Bkgd: all SM processes	
ΔP _e .	ΔP_{e+}	ΔP _{e-}	ΔP_{e+}	ΔP _e -	ΔP_{e+}
0.00155	0.00227	0.0021	0.0030	0.0020	0.0029
SiD 2f 4f 6f Bgnd Only SiD 2f 4f 6f Bgnd Only					